## Notice of References Cited

Application/Control No. 10/053,011	Applicant(s)/Patent Under Reexamination ACHARYA ET AL.		
Examiner	Art Unit		
April L Baugh	2141	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date · MM-YYYY	Name	Classification
	А	US-2002/0194498	12-2002	Blight et al.	713/201
	В	US-6,845,393	01-2005	Murphy et al.	709/220
	С	US-2003/0093496	05-2003	O'Connor et al.	709/217
,	D	US-6,513,061	01-2003	Ebata et al.	709/203
	E	US-6,785,542	08-2004	Blight et al.	455/426.1
	F	US-6,292,833	09-2001	Liao et al.	709/229
	G	US-2002/0062375	05-2002	Teodosiu et al.	709/226
	н	US-6,341,311	01-2002	Smith et al.	709/226
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Date Country Code-Number-Kind Code MM-YYYY Country		Country	Name Classificat	
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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